Commercial Announcements

Fully Integrated Diffractometry System for Powder Analysis

The PW1800 is a fully integrated diffractometry system for automated qualitative/quantitative powder analysis in research and industrial applications. The PW1800 incorporates a recently developed goniometer that combines high performance with ease of use and sturdy construction.

All diffractometer functions are automatically controlled by a built-in array of five microprocessors which respond to commands (a) stored in the memory, (b) entered via a keyboard terminal, or (c) received on-line from an external computer source. This simplicity of operation makes possible a wide range of routine analytical applications for which X-ray diffraction may not previously have been considered.

The PW1800 combines state of the art generator and goniometer technology in an integrated system designed for simple operation and high throughput. It is recommended for use in any R&D environment as well as in cement production, geology, mining and metallurgical processing and pharmaceutical manufacturing, among other industries.

XRD Software for Personal Computers

PC-APD is an easy to use analytical software package for the Philips IPD Integrated Powder Diffractometer, MPD1880 Multi-Purpose Diffractometer system and CPD Compact Powder Diffractometer.

Extensive use of menus and input forms make it simple for a user to set up automatic analysis programs very quickly, without the need to consult lengthy operating manuals.

Developed for IBM XT/AT/PS2 or compatible computers such as the Philips P3200 Series, the PC-APD software package offers an economical yet powerful means of system automation for powder diffractometry applications.

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EAS Short Courses

at the

28th Annual Eastern Analytical Symposium & Exposition September 24-29, 1989, New York Hilton Hotel, New York, N.Y.

"The Role of Modern X-Ray Diffraction Techniques in Chemical and Structural Analysis"

Lecturers: Ron Jenkins – International Centre for Diffraction Data
Graheme Williams – Enraf-Nonius
Drake Ellington – Smith Kline and French

Registration: Advance registration fees, $275 for 1 day course, $375 for 2 day course; includes registration for all technical sessions.

Call: EAS Hotline 302 453 0785 or
Write: EAS POB 633, Montchanin, Delaware 19710-0633

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